Lowering the cost of test for the newest double data rate (DDR) and Flash memory ICs demands an efficient test solution offering both performance and throughput. ADVANTEST’s M6245 test handler delivers industry-leading productivity while minimizing downtime, resulting in the most efficient and economical test solution for advanced memory devices.

**Pin-point positioning accuracy**

Using a precision visual-alignment system, the M6245 handler can achieve contact accuracy to within 0.3 mm ball pitch. In addition to improving test yields, this enables faster set-up and calibration for maximum throughput.

Visual alignment also allows the system to accommodate fine-pitch devices. For memory ICs with current pitch designs, the handler can be easily switched to mechanical alignment.

**Advanced thermal technology**

ADVANTEST’s proprietary dual-fluid design maintains the temperature of each DUT within ±1°C across the range of -20°C to 100°C and within ±2°C over the ranges of -40°C to -20.1°C and 100.1°C to 125°C. With this technology, devices that operate over wide temperature spans can be more accurately tested under real-world conditions.
Optimized for productivity

The handler’s highly automated operation is geared to achieve maximum productivity. For example, DUTs that do not pass functional testing on the first trial are automatically run through the system again for re-testing. This helps to ensure the highest possible yield while also reducing operators’ workloads.

In addition, the system is equipped with ADVANTEST’s handler data visualization framework, which allows the test cell’s status to be remotely monitored from any internet connection.